

25. (Currently Amended) A method for operating a probe that interacts with a surface of a sample, comprising:

scanning a region the surface of the sample with the probe;

manipulating the surface of the sample with the probe; **[and]**

selecting a subregion of the region; and

rescanning **[a]** **the selected** subregion of the region of the surface of the sample.

26. (Original) The method for operating a probe that interacts with a surface of a sample according to claim 25, wherein the manipulating step further comprises manipulating the surface of the sample with a probe other than the probe used to scan the region of the surface of the sample.

27. (Original) The method for operating a probe that interacts with a surface of a sample according to claim 25, wherein the manipulating step further comprises manipulating the surface of the sample with the probe used to scan the region of the surface of the sample.

28. (Original) The method for operating a probe that interacts with a surface of a sample according to claim 27, wherein

the manipulating step further comprises manipulating a subregion of the region of the surface of the sample with the probe, and

the rescanning step further comprises rescanning the manipulated subregion of the region of the surface of the sample.

29. (Original) The method for operating a probe that interacts with a surface of a sample according to claim 27, wherein the manipulating step further comprises manipulating particles on the surface of the sample with the probe.

30. (Original) The method for operating a probe that interacts with a surface of a sample according to claim 27, wherein the manipulating step further comprises manipulating particles on the surface of the sample by picking up the particles with the probe.

31. (Original) The method for operating a probe that interacts with a surface of a sample according to claim 25, wherein the probe comprises:

a cantilever;

a first tip mounted on the cantilever; and

a second tip mounted on the cantilever, the first and the second tip being configured to combine to form an imaging tip.

32. (Original) The method for operating a probe that interacts with a surface of a sample according to claim 31, further comprising applying a voltage across the first tip and the second tip to combine the first tip and the second tip to form an imaging tip.

33-73 (Cancelled)

74. (New) A method for operating a probe that interacts with a surface of a sample, comprising:

scanning a region of the surface of the sample with the probe;

manipulating the sample with the probe;

rescanning a subregion of the region of the surface of the sample; and

applying a voltage across the first tip and the second tip to combine the first tip and the second tip to form an imaging probe, wherein the probe comprises:

a cantilever;

a first tip mounted on a cantilever; and

a second tip mounted on the cantilever, the first and the second tips being configured to combine to form an imaging probe.